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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/540,319	PARK, HEE-BOONG	
Examiner	Art Unit	
Joel M. Lamprecht	3737	

SEARCHED			
Class	Subclass	Date	Examiner
600	427, 429, 461, 437, 440	4/24/2007	JML
600	130, 169	4/24/2007	JML
382	132, 284	4/24/2007	JML

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
1			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
International author search and attached east search history	4/24/2007	JML		
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